

SLOVENSKI STANDARD

SIST EN ISO 12179:2022

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Nadomešča:

SIST EN ISO 12179:2000

SIST EN ISO 12179:2000/AC:2008

Specifikacija geometrijskih veličin izdelka (GPS) - Tekstura površine: profilna metoda - Umerjanje kontaktnih (s tipalom) instrumentov (ISO 12179:2021)

Geometrical product specifications (GPS) - Surface texture: Profile method - Calibration of contact (stylus) instruments (ISO 12179:2021)

Geometrische Produktspezifikation (GPS) - Oberflächenbeschaffenheit: Tastschnittverfahren - Kalibrierung von Tastschnittgeräten (ISO 12179:2021)

Spécification géométrique des produits (GPS) - Etats de surface : Méthode du profil - Etalonnage des instruments à contact (palpeur) (ISO 12179:2021)

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Ta slovenski standard je istoveten z: EN ISO 12179:2022

ICS:

17.040.30	Merila	Measuring instruments
17.040.40	Specifikacija geometrijskih veličin izdelka (GPS)	Geometrical Product Specification (GPS)

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en,fr,de

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EUROPEAN STANDARD
NORME EUROPÉENNE
EUROPÄISCHE NORM

EN ISO 12179

January 2022

ICS 17.040.30

Supersedes EN ISO 12179:2000, EN ISO
12179:2000/AC:2008

English Version

**Geometrical product specifications (GPS) - Surface texture:
Profile method - Calibration of contact (stylus)
instruments (ISO 12179:2021)**

Spécification géométrique des produits (GPS) - Etats de
surface : Méthode du profil - Etalonnage des
instruments à contact (palpeur) (ISO 12179:2021)

Geometrische Produktspezifikation (GPS) -
Oberflächenbeschaffenheit: Tastschnittverfahren -
Kalibrierung von Tastschnittgeräten (ISO 12179:2021)

This European Standard was approved by CEN on 27 November 2021.

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EUROPEAN COMMITTEE FOR STANDARDIZATION
COMITÉ EUROPÉEN DE NORMALISATION
EUROPÄISCHES KOMITEE FÜR NORMUNG

CEN-CENELEC Management Centre: Rue de la Science 23, B-1040 Brussels

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European foreword

This document (EN ISO 12179:2022) has been prepared by Technical Committee ISO/TC 213 "Dimensional and geometrical product specifications and verification" in collaboration with Technical Committee CEN/TC 290 "Dimensional and geometrical product specification and verification" the secretariat of which is held by AFNOR.

This European Standard shall be given the status of a national standard, either by publication of an identical text or by endorsement, at the latest by July 2022, and conflicting national standards shall be withdrawn at the latest by July 2022.

Attention is drawn to the possibility that some of the elements of this document may be the subject of patent rights. CEN shall not be held responsible for identifying any or all such patent rights.

This document supersedes EN ISO 12179:2000.

Any feedback and questions on this document should be directed to the users' national standards body/national committee. A complete listing of these bodies can be found on the CEN website.

According to the CEN-CENELEC Internal Regulations, the national standards organizations of the following countries are bound to implement this European Standard: Austria, Belgium, Bulgaria, Croatia, Cyprus, Czech Republic, Denmark, Estonia, Finland, France, Germany, Greece, Hungary, Iceland, Ireland, Italy, Latvia, Lithuania, Luxembourg, Malta, Netherlands, Norway, Poland, Portugal, Republic of North Macedonia, Romania, Serbia, Slovakia, Slovenia, Spain, Sweden, Switzerland, Turkey and the United Kingdom.

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INTERNATIONAL STANDARD

ISO
12179

Second edition
2021-12

Geometrical product specifications (GPS) — Surface texture: Profile method — Calibration of contact (stylus) instruments

*Spécification géométrique des produits (GPS) — État de surface:
Méthode du profil — Étalonnage des instruments à contact (palpeur)*

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Foreword

ISO (the International Organization for Standardization) is a worldwide federation of national standards bodies (ISO member bodies). The work of preparing International Standards is normally carried out through ISO technical committees. Each member body interested in a subject for which a technical committee has been established has the right to be represented on that committee. International organizations, governmental and non-governmental, in liaison with ISO, also take part in the work. ISO collaborates closely with the International Electrotechnical Commission (IEC) on all matters of electrotechnical standardization.

The procedures used to develop this document and those intended for its further maintenance are described in the ISO/IEC Directives, Part 1. In particular, the different approval criteria needed for the different types of ISO documents should be noted. This document was drafted in accordance with the editorial rules of the ISO/IEC Directives, Part 2 (see www.iso.org/directives).

Attention is drawn to the possibility that some of the elements of this document may be the subject of patent rights. ISO shall not be held responsible for identifying any or all such patent rights. Details of any patent rights identified during the development of the document will be in the Introduction and/or on the ISO list of patent declarations received (see www.iso.org/patents).

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For an explanation of the voluntary nature of standards, the meaning of ISO specific terms and expressions related to conformity assessment, as well as information about ISO's adherence to the World Trade Organization (WTO) principles in the Technical Barriers to Trade (TBT), see www.iso.org/iso/foreword.html.

This document was prepared by Technical Committee ISO/TC 213, *Dimensional and geometrical product specifications and verification*, in collaboration with the European Committee for Standardization (CEN) Technical Committee CEN/TC 290, *Dimensional and geometrical product specification and verification*, in accordance with the Agreement on technical cooperation between ISO and CEN (Vienna Agreement).

This second edition cancels and replaces the first edition (ISO 12179:2000), which has been technically revised. It also incorporates Technical Corrigendum ISO 12179:2000/Cor. 1:2003.

The main changes to the previous edition are as follows:

— [Annex C](#) has been amended.

Any feedback or questions on this document should be directed to the user's national standards body. A complete listing of these bodies can be found at www.iso.org/members.html.

ISO 12179:2021(E)**Introduction**

This document is a geometrical product specification (GPS) standard and is to be regarded as a general GPS standard (see ISO 14638). It influences chain link G of the chain of standards on profile surface texture.

The ISO GPS matrix model is given in ISO 14638, For more detailed information on the relationship of this document to the GPS matrix model, see [Annex F](#). An overview of standards on profiles and areal surface texture is given in [Annex E](#).

This document introduces calibration of contact (stylus) instruments as defined in ISO 3274. The calibration is carried out with the aid of measurement standards.

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